

Peter G. Jones,^{a*}
Peter Bubentitschek,^b
Henning Hopf^b and
Bernhard Witulski^b^aInstitut für Anorganische und Analytische
Chemie, Technische Universität Braunschweig,
Postfach 3329, 38023 Braunschweig, Germany,
and ^bInstitut für Organische Chemie, Technische
Universität Braunschweig, Postfach 3329,
38023 Braunschweig, Germany

Correspondence e-mail: p.jones@tu-bs.de

Key indicators

Single-crystal X-ray study

T = 178 K

Mean $\sigma(\text{C}-\text{C}) = 0.009 \text{ \AA}$

R factor = 0.073

wR factor = 0.222

Data-to-parameter ratio = 10.0

For details of how these key indicators were
automatically derived from the article, see
<http://journals.iucr.org/e>.

A dimer of 7-cyanodibenzobarrelene

The molecule of the title compound, 2,3-dicyanotetrabenzopentacyclo[8.2.2.2^{4,7}.0^{2,9}.0^{3,8}]hexadeca-5,11,13,15-tetraene chloroform monosolvate, $\text{C}_{34}\text{H}_{22}\text{N}_2 \cdot \text{CHCl}_3$, displays approximate twofold symmetry. The four-membered ring has slightly lengthened C—C bonds and a ring pucker of 11.9 (7)°. The solvent molecule is involved in a C—H... π contact.

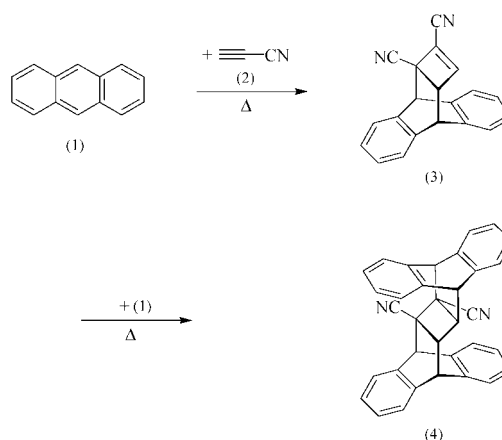
Received 6 January 2003

Accepted 8 January 2003

Online 17 January 2003

Comment

Heating a solution of anthracene, (1), and cyanoacetylene, (2), in a 1:4 molar ratio in benzene at 433 K results in the formation of a complex mixture of cycloadducts (Hopf & Witulski, 1995), among them the 1:2 adduct, (3), and a 2:2 adduct, (4), isolated in 4% yield, the structure of which we were unable to derive from spectroscopic data alone. The compound was therefore subjected to X-ray structure determination, the results of which are presented here, confirming structure (4).



Although several mechanisms can be proposed to account for the formation of the triply layered product, (4), the one involving the addition of excess (1) to the intermediate (3) is particularly attractive. Indeed, when (3) and (1) are heated in toluene at 433 K (ratio 1:2), compound (4), which is formally a head-to-tail dimer of 7-cyanodibenzobarrelene, was produced in 18% yield.

Compound (4) (Fig. 1) displays no imposed symmetry, but has approximate twofold symmetry. It crystallizes with one molecule of chloroform. Molecular dimensions may be regarded as normal, *e.g.* the four-membered ring displays slightly lengthened C—C bonds and a ring pucker of 11.9 (7)° (Allen, 1984). The exocyclic bonds C9—C11 and C9'—C11' are also significantly lengthened (Table 1).

The crystal packing involves three contacts that might be classified as C—H... X hydrogen bonds ($X = \text{N}$ or Cl ; Table 2). A more significant interaction, however, is between the

chloroform H atom and the centroid (*Cent*) of ring C1A'–C4A', with an H···*Cent* distance of 2.65 Å (non-normalized) and a C–H···*Cent* angle of 160°.

Experimental

The compound was prepared according to Witulski (1992) and recrystallized from chloroform/pentane.

Crystal data

C₃₄H₂₂N₂·CHCl₃
M_r = 577.90
 Orthorhombic, *P*2₁2₁2₁
a = 10.626 (4) Å
b = 16.048 (5) Å
c = 16.580 (7) Å
V = 2827.3 (18) Å³
Z = 4
D_x = 1.358 Mg m⁻³

Mo *K*α radiation
 Cell parameters from 50 reflections
 θ = 10–11°
 μ = 0.35 mm⁻¹
T = 178 (2) K
 Prism, colourless
 0.7 × 0.4 × 0.2 mm

Data collection

Nicolet R3 diffractometer
 ω scans
 Absorption correction: none
 3618 measured reflections
 3618 independent reflections
 2199 reflections with *I* > 2σ(*I*)
 θ_{\max} = 27.5°

h = –13 → 0
k = –20 → 0
l = –21 → 0
 3 standard reflections every 147 reflections
 intensity decay: none

Refinement

Refinement on *F*²
R[*F*² > 2σ(*F*²)] = 0.074
wR(*F*²) = 0.222
S = 1.03
 3618 reflections
 361 parameters
 H-atom parameters constrained

$w = 1/[\sigma^2(F_o^2) + (0.087P)^2 + 5.5143P]$
 where $P = (F_o^2 + 2F_c^2)/3$
 $(\Delta/\sigma)_{\max} < 0.001$
 $\Delta\rho_{\max} = 1.08 \text{ e } \text{Å}^{-3}$
 $\Delta\rho_{\min} = -0.97 \text{ e } \text{Å}^{-3}$
 Absolute structure: Flack (1983), no Friedel pairs
 Flack parameter = 0.4 (2)

Table 1

Selected geometric parameters (Å, °).

C9–C11	1.602 (9)	C12–C12'	1.560 (8)
C11–C12	1.563 (8)	C9'–C11'	1.589 (9)
C11–C11'	1.571 (9)	C11'–C12'	1.578 (8)
C12–C11–C11'	89.4 (4)	C11–C11'–C12'	89.5 (4)
C12'–C12–C11	90.5 (4)	C12–C12'–C11'	89.3 (4)
C11'–C11–C12–C12'	8.5 (5)		

Table 2

Hydrogen-bonding geometry (Å, °).

<i>D</i> –H··· <i>A</i>	<i>D</i> –H	H··· <i>A</i>	<i>D</i> ··· <i>A</i>	<i>D</i> –H··· <i>A</i>
C2–H2···N ⁱ	0.95	2.70	3.641 (9)	172
C6'–H6'···N ⁱⁱ	0.95	2.59	3.455 (9)	152
C9–H9···C11 ⁱⁱⁱ	1.00	2.82	3.776 (7)	161

Symmetry codes: (i) $\frac{1}{2} - x, 1 - y, z - \frac{1}{2}$; (ii) $\frac{3}{2} - x, 1 - y, z - \frac{1}{2}$; (iii) $x - 1, y, z$.

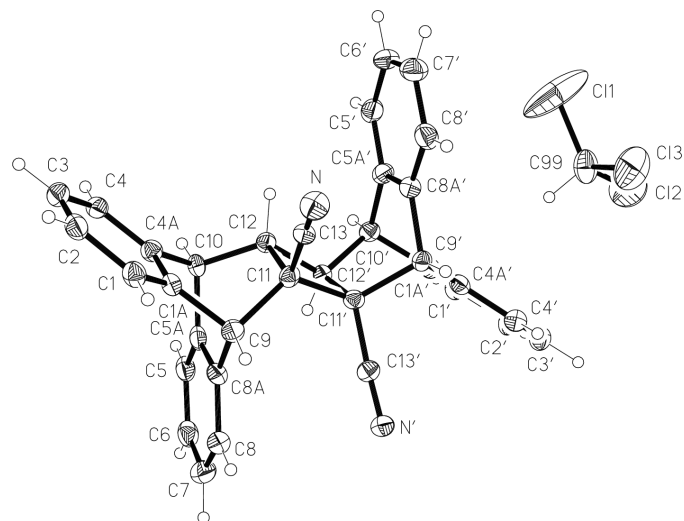


Figure 1

The structure of the asymmetric unit. Displacement ellipsoids are drawn at the 30% probability level and H-atom radii are arbitrary.

H atoms were included using a riding model with fixed C–H bond lengths (aromatic = 0.95 Å and methine = 1.00 Å); *U*_{iso}(H) values were fixed at 1.2*U*_{eq} of the parent atom. The Flack (1983) parameter was indeterminate. The only major features of residual electron density are found in the solvent region.

Data collection: *P3* (Nicolet, 1987); cell refinement: *P3*; data reduction: *XDISK* (Nicolet, 1987); program(s) used to solve structure: *SHELXS97* (Sheldrick, 1990); program(s) used to refine structure: *SHELXL97* (Sheldrick, 1997); molecular graphics: *XP* (Siemens, 1994); software used to prepare material for publication: *SHELXL97*.

Financial support from the Fonds der Chemischen Industrie is gratefully acknowledged. We thank Mr A. Weinkauff for technical assistance.

References

- Allen, F. H. (1984). *Acta Cryst.* **B40**, 64–72.
 Flack, H. D. (1983). *Acta Cryst.* **A39**, 876–881.
 Hopf, H. & Witulski, B. (1995). *Modern Acetylene Chemistry*, edited by P. J. Stang & F. Diederich, pp. 33–66. Weinheim: VCH Verlagsgesellschaft.
 Nicolet (1987). *P3* and *XDISK*. Nicolet X-ray Instrument Corporation, Madison, Wisconsin, USA.
 Sheldrick, G. M. (1990). *Acta Cryst.* **A46**, 467–473.
 Sheldrick, G. M. (1997). *SHELXL97*. University of Göttingen, Germany.
 Siemens (1994). *XP*. Version 5.03. Siemens Analytical X-ray Instruments Inc., Madison, Wisconsin, USA.
 Witulski, B. (1992). PhD thesis, Technical University of Braunschweig, Germany.